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Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,973	CHO ET AL.
Examiner	Art Unit

3672

Matthew J. Smith

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Class	Subclass	Date	Examiner
166	285, 386, 387, 381, 118, 231,	3/15/2006	MS MS
	135, 192,		
	241.6,		
	241.7,		
	207		
175	325.1-		
	325.7		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			<u> </u>

	DATE	EXMR
Consulted: W. Neuder, classes 166, 175	3/15/2006	MS MS